RELIABILITY REPORT
FOR
MAX1472AKA+
PLASTIC ENCAPSULATED DEVICES

October 1, 2009

MAXIM INTEGRATED PRODUCTS
120 SAN GABRIEL DR.
SUNNYVALE, CA 94086

Approved by

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<td>Approved by</td>
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<tr>
<td>Ken Wendel</td>
<td>Quality Assurance</td>
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<td>Director, Reliability Engineering</td>
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The MAX1472AKA+ successfully meets the quality and reliability standards required of all Maxim products. In addition, Maxim’s continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim’s quality and reliability standards.

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I. Device Description

A. General

The MAX1472 is a crystal-referenced phase-locked loop (PLL) VHF/UHF transmitter designed to transmit OOK/ASK data in the 300MHz to 450MHz frequency range. The MAX1472 supports data rates up to 100kbps, and adjustable output power to more than +10dBm into a 50Ω load. The crystal-based architecture of the MAX1472 eliminates many of the common problems with SAW transmitters by providing greater modulation depth, faster frequency settling, higher tolerance of the transmit frequency, and reduced temperature dependence. Combined, these improvements enable better overall receiver performance when using a superheterodyne receiver such as the MAX1470 or MAX1473. The MAX1472 is available in a 3mm x 3mm 8-pin SOT23 package and is specified for the automotive (-40°C to +125°C) temperature range. An evaluation kit is available. Contact Maxim Integrated Products for more information.
II. Manufacturing Information

A. Description/Function: 300MHz-to-450MHz Low-Power, Crystal-Based ASK Transmitter
B. Process: TS35
C. Number of Device Transistors:
D. Fabrication Location: Taiwan
E. Assembly Location: Malaysia
F. Date of Initial Production: April 22, 2003

III. Packaging Information

A. Package Type: 8-pin SOT23
B. Lead Frame: Copper Alloy
C. Lead Finish: 100% matte Tin
D. Die Attach: Non-conductive Epoxy
E. Bondwire: Gold (1 mil dia.)
F. Mold Material: Epoxy with silica filler
G. Assembly Diagram: #05-9000-1715
H. Flammability Rating: Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard J-STD-020-C: Level 1
J. Single Layer Theta Jb: 112°C/W
K. Single Layer Theta Jc: 80°C/W

IV. Die Information

A. Dimensions: 52 X 32 mils
B. Passivation: Si₃N₄/SiO₂ (Silicon nitride/ Silicon dioxide)
C. Interconnect: Al/0.5%Cu with Ti/TiN Barrier
D. Backside Metallization: None
E. Minimum Metal Width: 0.35µm
F. Minimum Metal Spacing: 0.35µm
G. Bondpad Dimensions: 5 mil. Sq.
H. Isolation Dielectric: SiO₂
I. Die Separation Method: Wafer Saw
V. Quality Assurance Information

A. Quality Assurance Contacts: Ken Wendel (Director, Reliability Engineering)
   Bryan Preeshl (Managing Director of QA)

B. Outgoing Inspection Level: 0.1% for all electrical parameters guaranteed by the Datasheet.
   0.1% For all Visual Defects.

C. Observed Outgoing Defect Rate: < 50 ppm

D. Sampling Plan: Mil-Std-105D

VI. Reliability Evaluation

A. Accelerated Life Test

   The results of the 135°C biased (static) life test are shown in Table 1. Using these results, the Failure Rate ($\lambda$) is calculated as follows:

   \[
   \lambda = \frac{1}{MTTF} = \frac{1.83}{192 \times 4340 \times 47 \times 2} \quad \text{(Chi square value for MTTF upper limit)}
   \]

   \[
   \lambda = 22.8 \times 10^{-9}
   \]

   \[
   \lambda = 22.8 \text{ F.I.T.} \ (60\% \text{ confidence level @ 25°C})
   \]

   The following failure rate represents data collected from Maxim's reliability monitor program. Maxim performs quarterly life test monitors on its processes. This data is published in the Reliability Report found at http://www.maxim-ic.com/qa/reliability/monitor. Cumulative monitor data for the TS35 Process results in a FIT Rate of 0.11 @ 25C and 1.93 @ 55C (0.8 eV, 60% UCL)

B. Moisture Resistance Tests

   The industry standard 85°C/85%RH or HAST testing is monitored per device process once a quarter.

C. E.S.D. and Latch-Up Testing

   The SC72 die type has been found to have all pins able to withstand a HBM transient pulse of +/-2500 V per JEDEC JESD22-A114. Latch-Up testing has shown that this device withstands a current of +/-250 mA.
<table>
<thead>
<tr>
<th>TEST ITEM</th>
<th>TEST CONDITION</th>
<th>FAILURE IDENTIFICATION</th>
<th>SAMPLE SIZE</th>
<th>NUMBER OF FAILURES</th>
</tr>
</thead>
<tbody>
<tr>
<td><strong>Static Life Test</strong></td>
<td>Ta = 135°C</td>
<td>DC Parameters &amp; functionality</td>
<td>47</td>
<td>0</td>
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<tr>
<td>(Note 1)</td>
<td>Biased</td>
<td></td>
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<tr>
<td>Time = 192 hrs.</td>
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<tr>
<td><strong>Moisture Testing</strong></td>
<td>Ta = 130°C</td>
<td>DC Parameters &amp; functionality</td>
<td>77</td>
<td>0</td>
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<tr>
<td>(Note 2)</td>
<td>RH = 85%</td>
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<td></td>
<td></td>
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<tr>
<td>HAST</td>
<td>Biased</td>
<td></td>
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<tr>
<td>Time = 96 hrs.</td>
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<tr>
<td><strong>Mechanical Stress</strong></td>
<td>-65°C/150°C</td>
<td>DC Parameters &amp; functionality</td>
<td>77</td>
<td>0</td>
</tr>
<tr>
<td>(Note 2)</td>
<td>1000 Cycles</td>
<td></td>
<td></td>
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<tr>
<td>Cycle</td>
<td>Method 1010</td>
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Note 1: Life Test Data may represent plastic DIP qualification lots.

Note 2: Generic Package/Process data